

TECHNOLOGY WORKSHOP PROGRAM

automotive  
**testing** EXPO 2011  
*north america* 

October 25, 26 and 27, 2011

THE SUBURBAN COLLECTION SHOWPLACE,  
NOVI, DETROIT, MI, USA

 SUBURBAN COLLECTION  
SHOWPLACE

North America's ONLY automotive test, evaluation  
and quality engineering trade show

**SHOW TIMES**

October 25 09.00hrs – 17.00hrs

October 26 09.00hrs – 17.00hrs

October 27 09.00hrs – 15.00hrs



Register online NOW to receive your FREE  
visitor pass/badge and avoid delays at registration!

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Greg Conner  
Chief Engineer  
Corner Tech

VISITOR

[www.testing-expousa.com](http://www.testing-expousa.com)

# automotive testing expo 2011

north america 



October 25, 26 and 27, 2011

ASAM (Association for Standardisation of Automation and Measuring Systems) will once again jointly host the Open Technology Forum at Automotive Testing Expo North America 2011.

Following the huge success at Automotive Testing Expo last year, ASAM has put together a comprehensive three-day Open Technology Forum with presentations from leading OEMs and Tier 1 and 2 suppliers.

The Open Technology Forum is **free of charge to attend**, and will commence each morning of the show.

## TUESDAY OCTOBER 25, 2011

### TESTBEDS AND SYSTEMS INTEGRATION

- 10:15 Effectively using torque sensors with today's data acquisition systems  
*Chris Novak, Honeywell*
- 10:40 J1939-82 compliance testing  
*George Bracken, business development manager, Open Networks, Vector CANtech Inc*
- 11:05 Sporadic system fault tracking in remote, mobile measurements: a case study utilizing imc LINK  
*Paul Nylander, general manager, imc Data Works LLC*
- 11:30 Fast ECU access for measurement and calibration on the testbed  
*Charles Kammerer, portfolio manager, AVL List GmbH*

### TEST DATA MANAGEMENT, CALIBRATION DATA MANAGEMENT

- 11:55 A practical approach to a supplier independent ODS Solution  
*Keith Butler, general manager, rd electronic LLC*
- 12:20 ASAM ODS web services  
*Christoph Niessen, senior engineer, Daimler Trucks*
- 12:45 Translating existing data models and file formats to ASAM ODS data store  
*Derrick Snyder, National Instruments*
- 13:10 Managing measurement data in parallel between ASAM ODS and data files  
*Derrick Snyder, National Instruments*
- 13:35 Aligning test execution with the development lifecycle  
*Christoph Braeuchle, MKS, a PTC Company*

### VEHICLE DIAGNOSTICS IN DEVELOPMENT, PRODUCTION AND SERVICE

- 14:00 Diagnostic communication with ASAM-MCD, ODX and UDS on CAN  
*Peter Subke, key account manager, Softing Automotive Electronics GmbH*
- 14:25 ASAM-MCD and ODX-based open test sequence exchange format (OTX)  
*Peter Subke, key account manager, Softing Automotive Electronics GmbH*
- 14:50 Strategies and techniques for restbus simulation  
*Noah Reding, product manager, National Instruments*
- 15:15 Standardizing your current and future vehicle network applications  
*Noah Reding, product manager, National Instruments*
- 15:40 Comparison of OBD scan-tool diagnostics for vehicles and heavy-duty trucks  
*Greg Potter, DG Technologies*



## WEDNESDAY OCTOBER 26, 2011

### SIMULATION / HARDWARE IN THE LOOP

- 10:15 Electric vehicle simulation for testing and validation  
*Matthew Eurich, president, Wineman Technology*
- 10:40 Hardware-in-the-loop simulation 101: introduction to HIL testing  
*Nick Keel, National Instruments*
- 11:05 Taking your .M files to a real-time OS just got W A Y easier  
*Jeffrey Phillips, LabVIEW product manager, National Instruments*
- 11:30 Virtual integration and test of automotive ECUs  
*Dr Jakob Mauss, QTronic GmbH*

### TEST AUTOMATION IN REAL AND SIMULATED ENVIRONMENTS

- 11:55 Unification of real and virtual worlds in the automotive industry using ASAM ODS  
*Raghavendra Kulkarni, business development manager, Robert Bosch Engineering and Business Solutions Ltd*
- 12:20 New technologies for integrating large-scale automotive test cells  
*Elizabeth Smith, National Instruments*
- 12:45 Intelligent test-case generation and automation for real-time test systems  
*Dr Mugur Tatar, QTronic GmbH*
- 13:10 Improve software quality and development efficiency with test component reuse  
*Nick Keel, National Instruments*
- 13:35 Very inexpensive CANbus ECU for simulation, gateway and test  
*John Brooks, field support engineer, Intrepid Control Systems Inc*
- 14:00 Integrating model-based control into real-life test cell applications  
*Darryn LaZar, vice president Sales & Marketing, Wineman Technology*

### MEASUREMENT, CALIBRATION AND TEST DATA ACQUISITION

- 14:25 Why should I care about performing inline analysis?  
*Jeffrey Phillips, LabVIEW product manager, National Instruments*
- 14:50 QuantumX: universal tool for efficient data acquisition  
*Jens Boersch, HBM*
- 15:15 Cost and feature scalable data logger platform  
*Colt Correa, vice president, Intrepid Control Systems Inc*
- 15:40 Dynamic MEMS feedback sensor testing for automotive systems  
*Robert Mitchell, Ideal Aerosmith*
- 16:05 Next Cycle and Same Cycle Control with Real-Time Combustion Analysis  
*Gary Parente, product marketing engineer, National Instruments*

## THURSDAY OCTOBER 27, 2011

### EVALUATION AND ANALYSIS OF TEST DATA

- 10:15 Whodunit? Your car battery is dead!  
*Dave Robins, president, Intrepid Control Systems Inc*
- 10:40 Making 3D measurement possible in climatic extremes  
*Phillip Lewis, technical engineering manager, Primetime Testing Laboratory*
- 11:05 Driving testing transformations with test maturity models: a pragmatic approach for evaluating testing maturity in organizations  
*Manish Jamadagni, senior manager - Business Development for Testing Services, L & T Infotech*
- 11:30 Analyzing data from ISO 14229, CCP, and XCP  
*Jeffery Quesnelle, senior software engineer, Intrepid Control Systems Inc*
- 11:55 How PSA uses the ASAM ODS standard  
*Laurent Nourry, IT project manager, PSA Peugeot Citroën*
- 12:20 Rubber meets the road in tire testing: changing the paradigm in how cars are developed  
*Dr Jim Cuttino, president / CEO, Camber Ridge LLC*
- 12:45 Finite element verification simplified with laser vibrometry  
*Sean Hollands, vice president of Sales, Polytec Inc*
- 13:10 Optimization of die-casting processes using infrared thermography  
*Jon Chynoweth, NEC Avio Infrared Technologies*
- 13:35 Damped accelerometers for crash testing  
*Ron Poff, Measurement Specialties Inc*